Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/655,229	CHANG, CHUNG NAN
Examiner	Art Unit
Shin-Hon Chen	2131

SEARCHED					
Class	Subclass	Date	Examiner		
380	277, 282	12/22/2005	S.C.		
713	171	12/22/2005	S.C.		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
	:					

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
USPAT, PGPUB, JPO, EPO, DERWENT	12/22/2005	S.C.
Consulted with Appeal Conference	12/22/2005	S.C.